



IEEE SW Test Workshop

Semiconductor Wafer Test Workshop



introduces:

The Probe Card Analyzer M5

Swtw 2011

Large Probe Cards

- Heavy and cumbersome to handle
- Large card repair is a pain in the back
- Large card repair is a logistical challenge

BE's M5 large probe card analyser - repair tool

- Takes the load of your back
- Boost working pleasure on large probe cards

See how



BE Engineering

- **Over 10 years experience in probe card testing equipment**
- **First with diamant scratch image viewing window as a standard**
- **First to apply carbon for ultra stiff flipping tabel**
- **Stuck to its vision on testing and repair, resulting in excellent ergonomics and throughput time**



The Probe Card Analyzer M5

- *Manager 5*

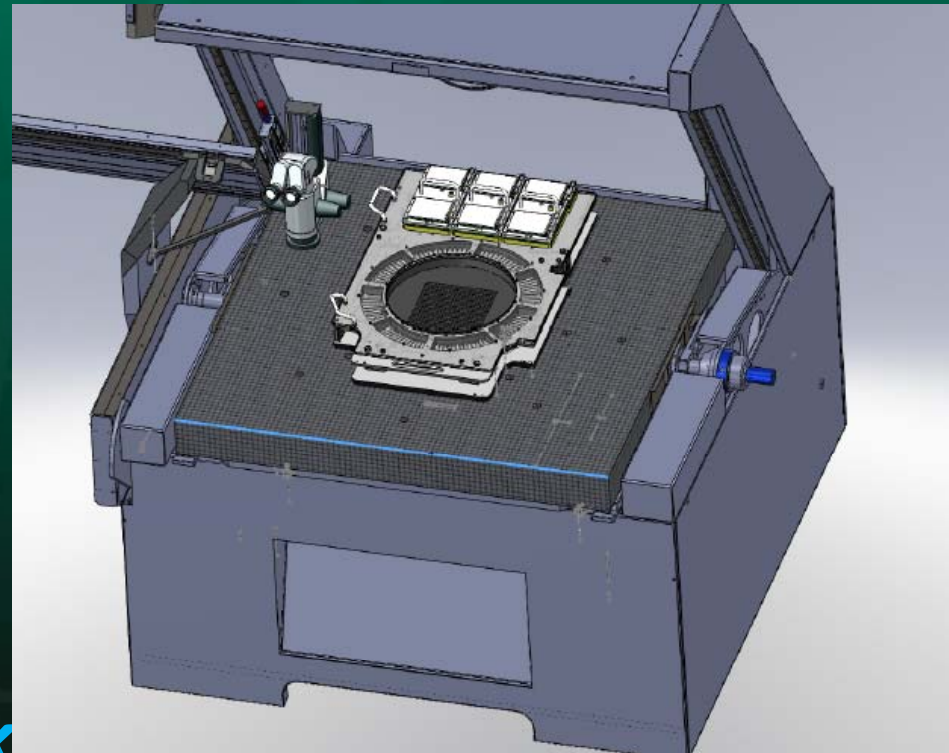


System overview M5

- *Fully dedicated system*
- *High speed*
- *Handle high channel count*
- *High load*
- *Protects your future investments*

The facts of the M5

- *450 mm and smaller*
- *Planarity*
- *Alignement*
- *Contact resistance*
- *Leakage*
- *Open and Short*
- *Contact Force*
- *Ergonomic Rework*

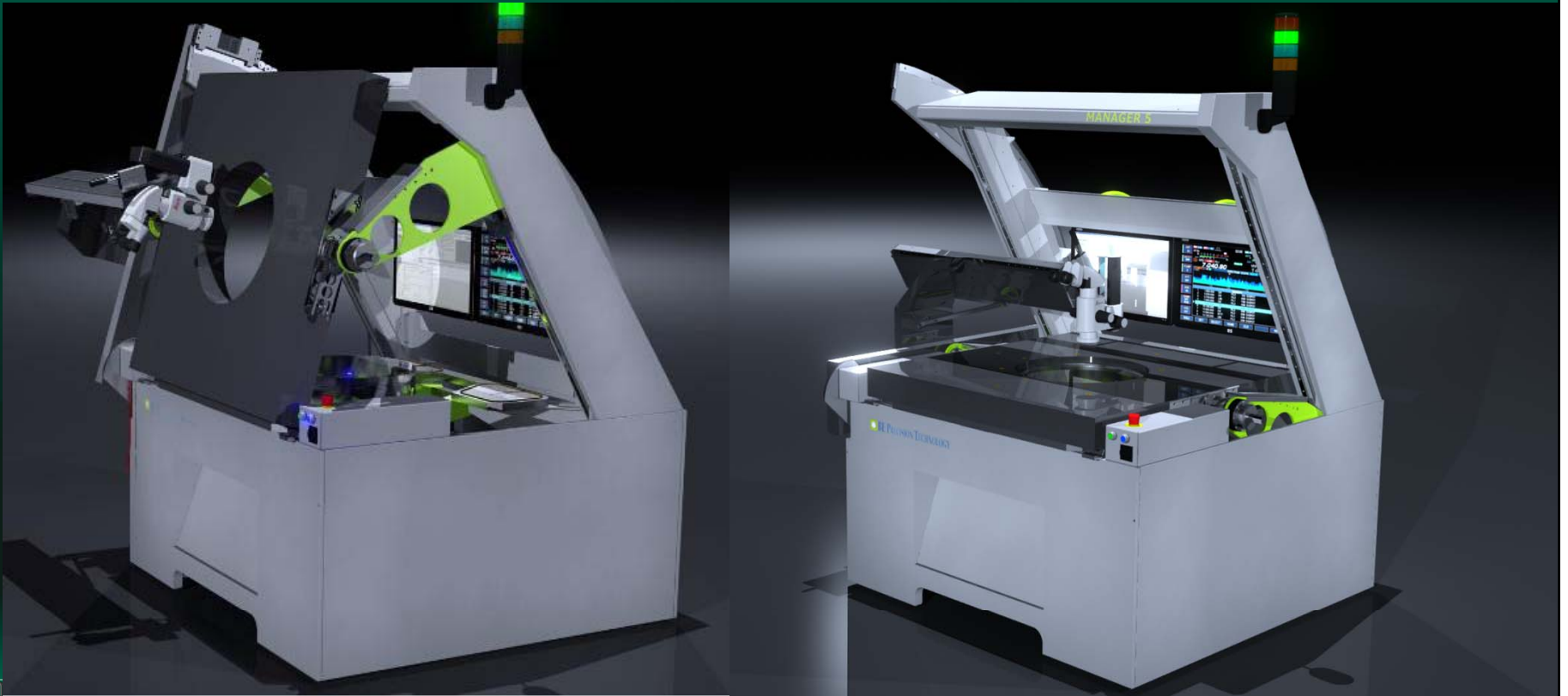


The facts of the M5

- *Z-force 600 kilo pressure*
- *Accuracy in Z 0.1 micron*
- *Alignement 0.1 micron*
- *Cres 10 Milli-ohm*
- *Leakage 0.1 Nano-Amp*
- *Motherboard size max. 1.2 meter*
- *Total max. probe pressure 600 kilogram force*
- *Channel count > 100K*

Options for repairs

- *Motorized flipping table*
- *Motorized microscope*

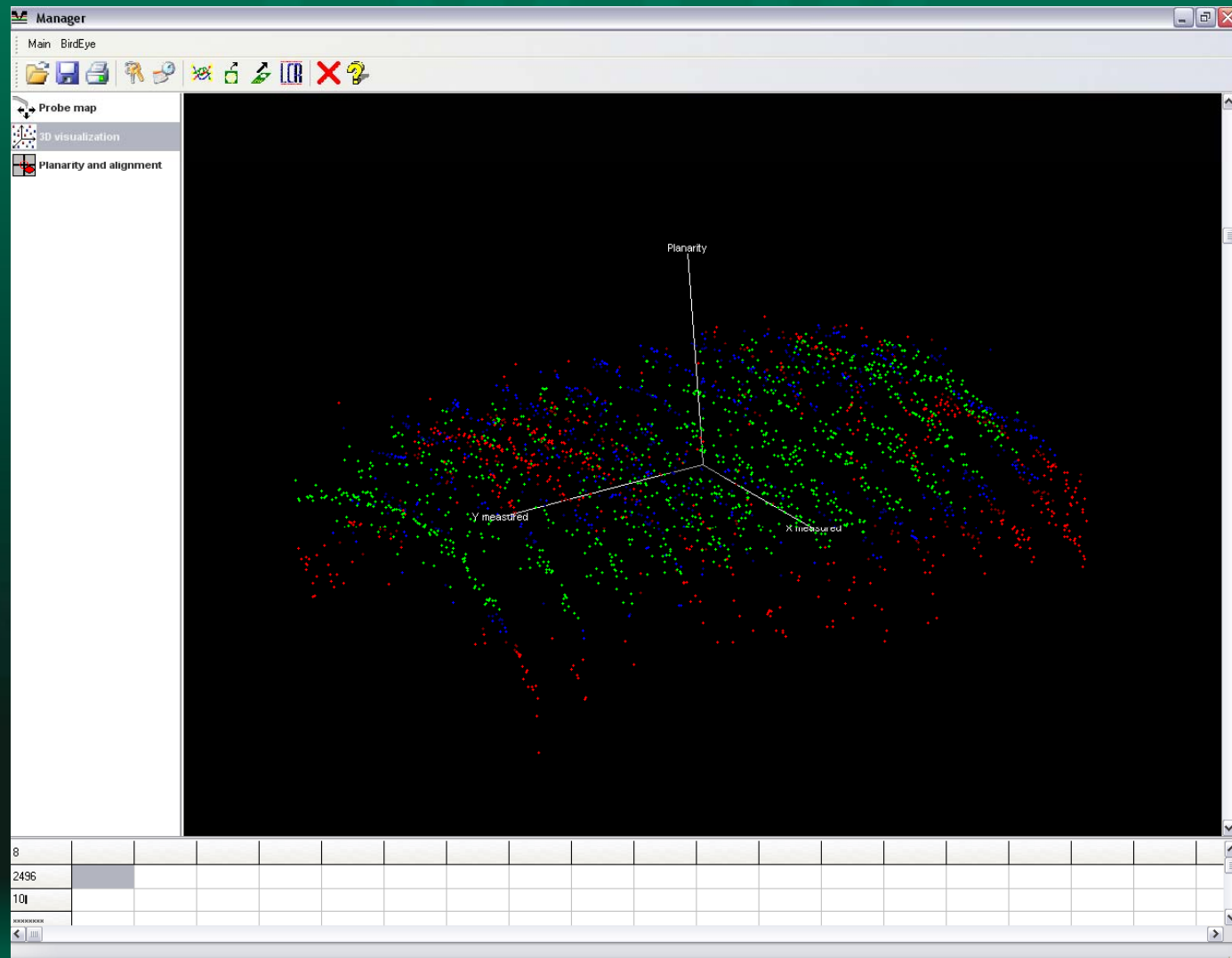


Features for analyzing

- *Optics for MEMS sample photo with resolution less than 0.5 micron*
- *Dedicated Wave length*
- *Variable zoom optics*

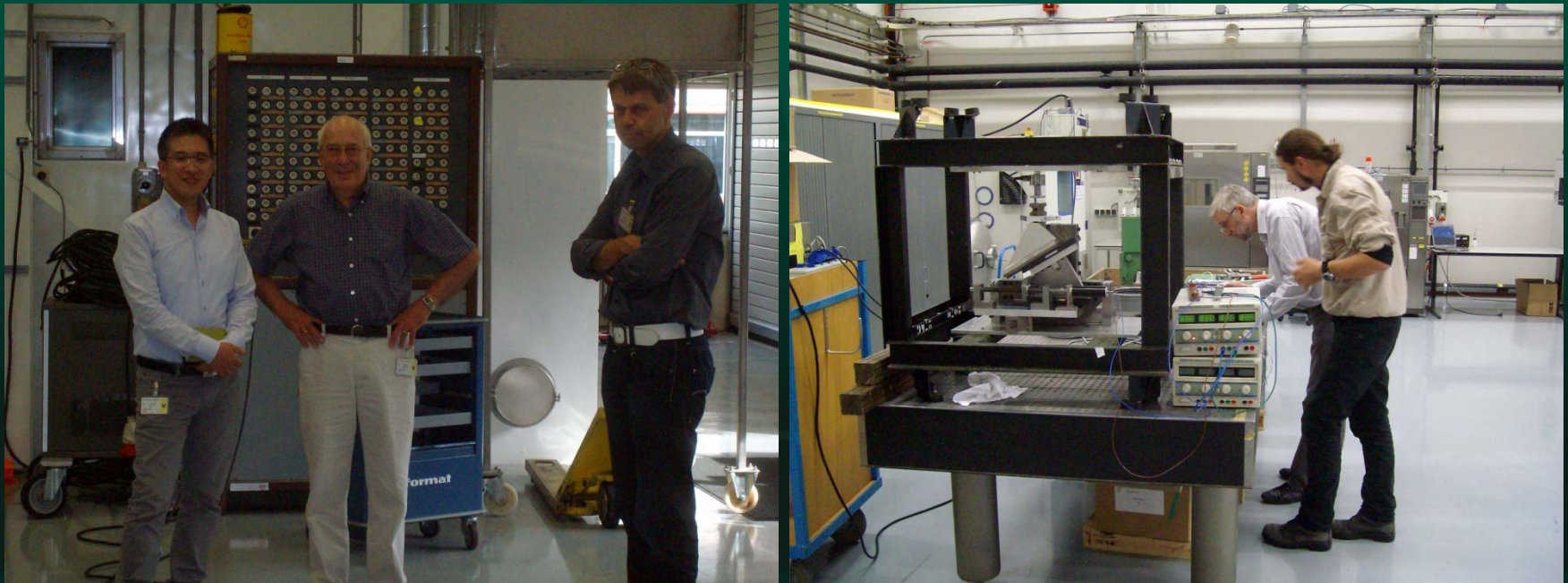


3D-view op probe positions



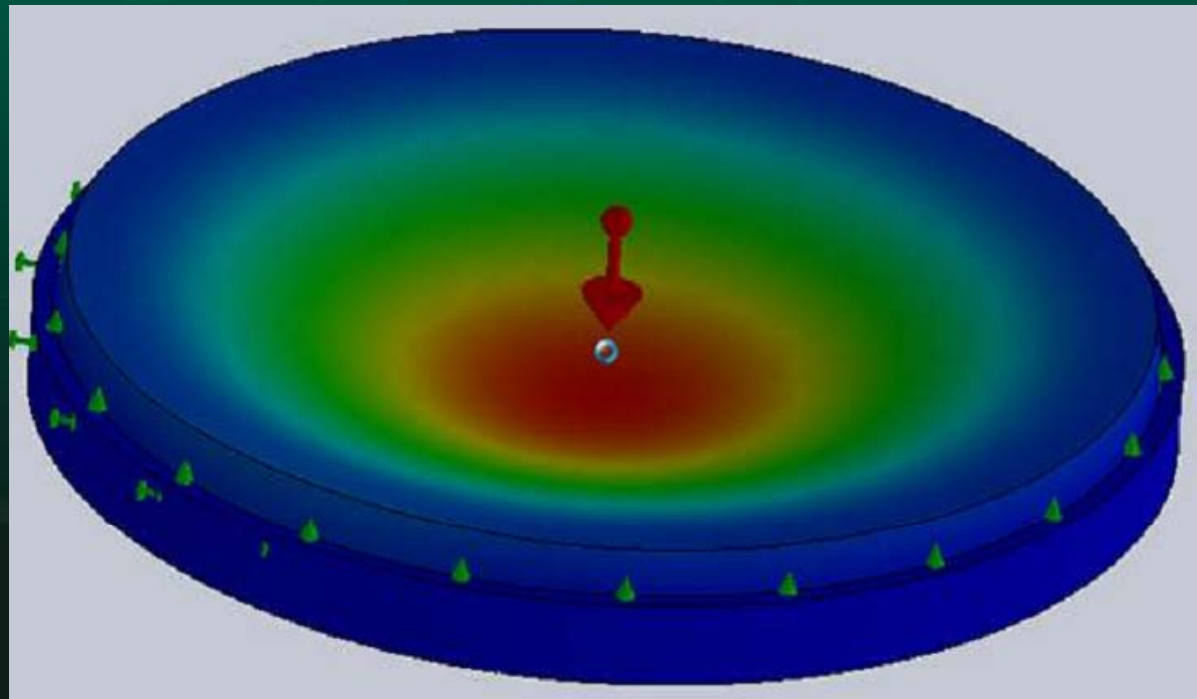
System under test

- *Independant inspection of specs. with the customer at Thales Netherlands*



System deformation

- *Glass plate for pressure measurement*



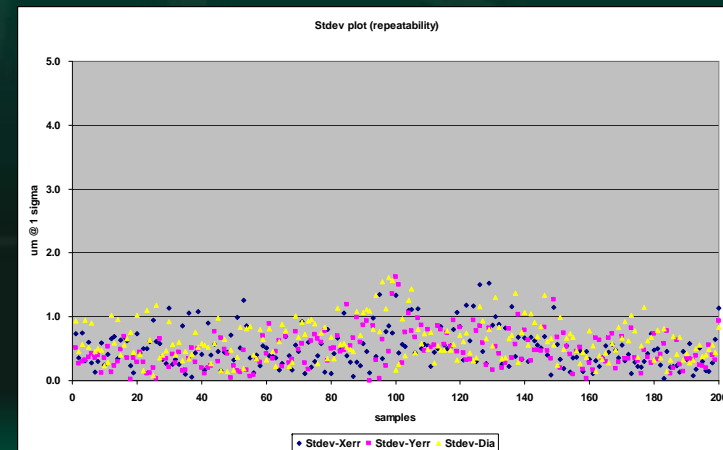
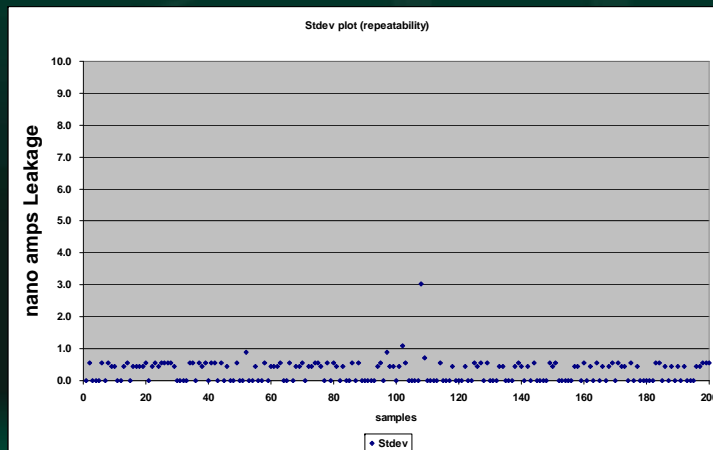
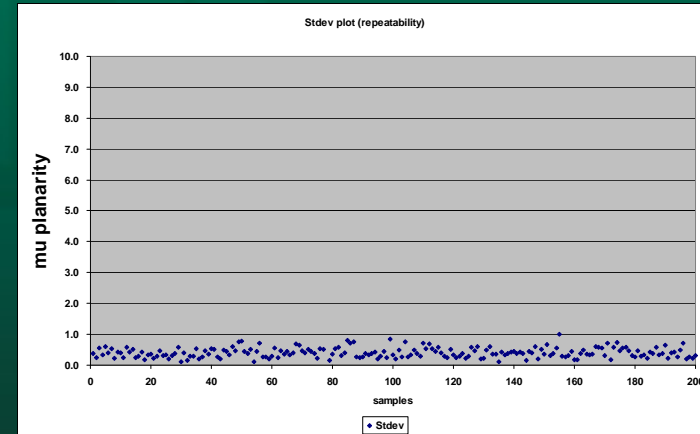
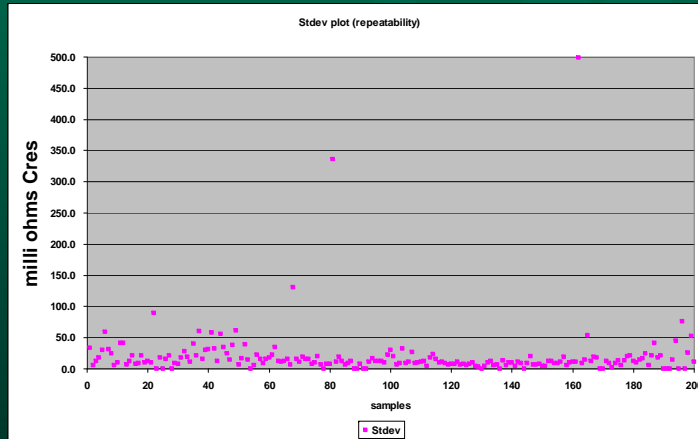
System deformation

- *Extreme high stiffness carbon flipping table*



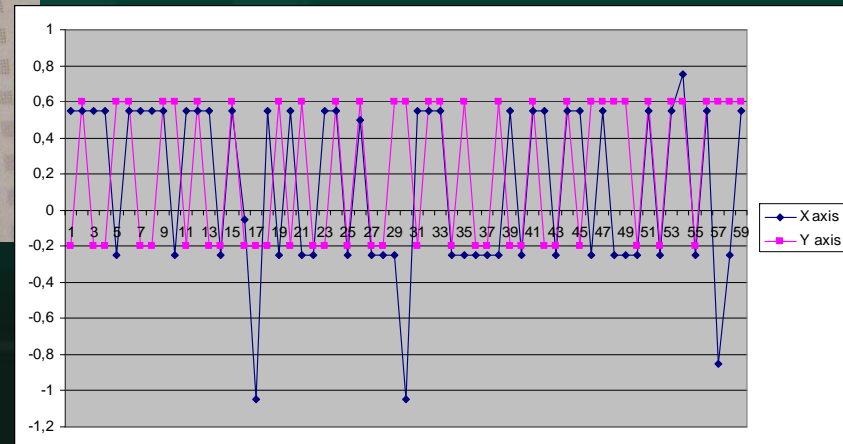
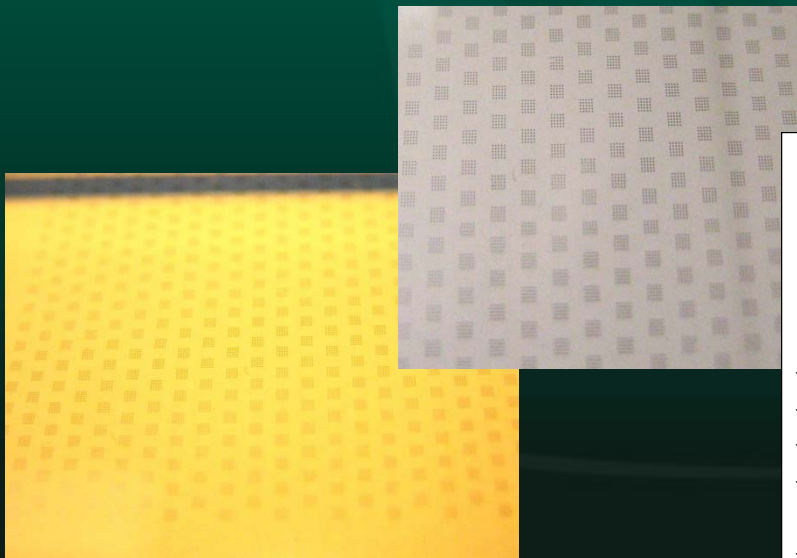
Repeatability

- *Graphics of some measurement results*



Absolute measurement

- *Values measuring glass mask*



PROBE ARRAY™

In cooperation with for lending their probecard

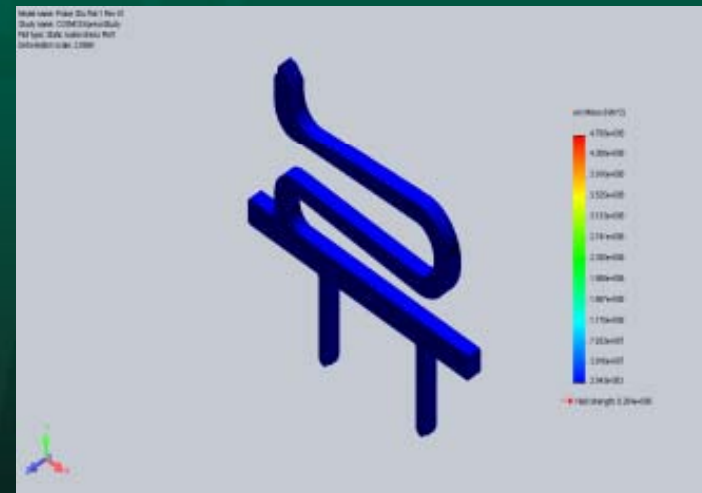
“The M5 is an analyzer that can truly test our MEMS probe heads-
Thanks BE”

➤ MEMS MicroBlade Probe

- ❖ Prefabricated & Assembled
- ❖ Low Force (<2grams)
- ❖ Long Life (>1,000,000 cycles)
- ❖ Coaxial Matched Impedance
- ❖ Replaceable in the field

➤ MEMS Photolithographic Probe

- ❖ Mask Generated Arrays
- ❖ Tiled Assembly
- ❖ Carbon Nano Hook & Loop
- ❖ Low Force (<2grams)
- ❖ Long Life (>1,000,000 cycles)
- ❖ Replaceable in the field

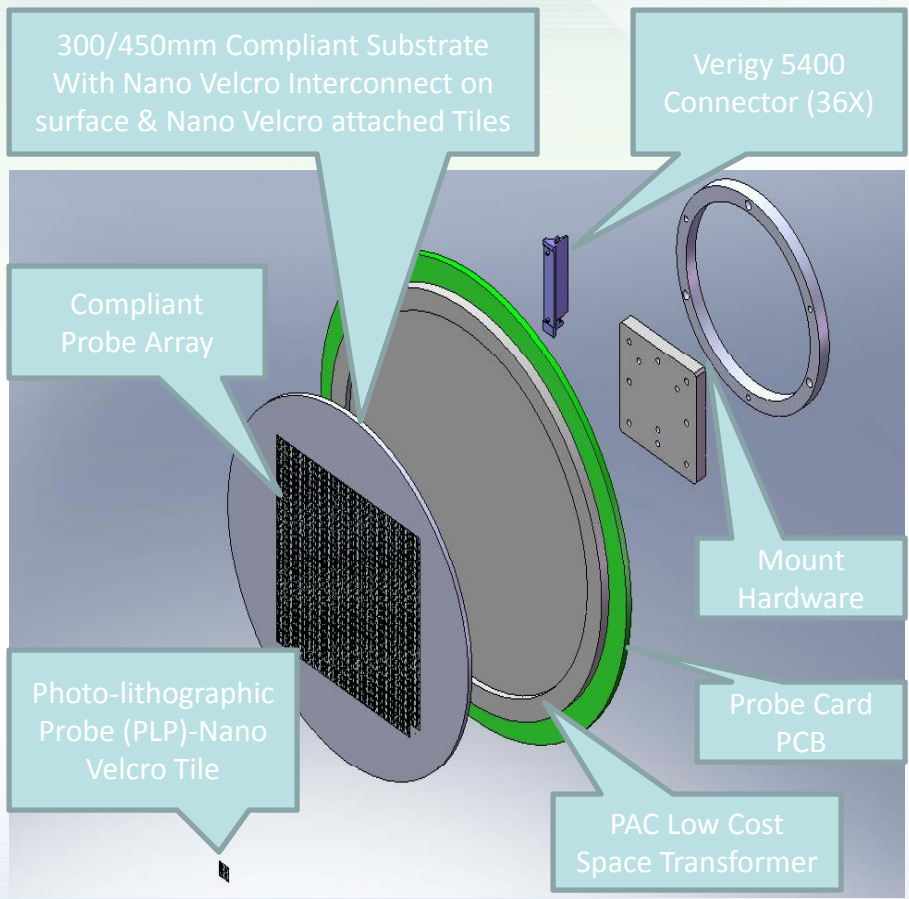




PROBE ARRAY™

Probe Card Assembly

Compliant 300 & 450mm Single Touchdown



System overview M5

- *Fully dedicated system (designed for 450 mm MEMS)*
- *Speed (direct rework and testing)*
- *Channels (over 100K)*
- *Load (over 600 kgf)*
- *Protects your future investments (300 mm mems and higher)*

Questions?

